

RoHS Compliant Product

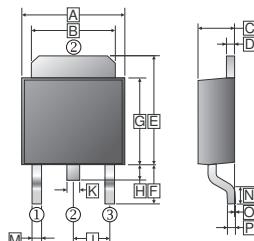
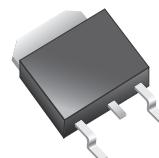
A suffix of "C" specifies halogen free

## DESCRIPTION

These miniature surface mount MOSFETs utilize a high cell density trench process to provide Low R<sub>DS(on)</sub> and to ensure minimal power loss and heat dissipation.

Typical applications are DC-DC converters and power management in portable and battery-powered products such as computers, printers, PCMCIA cards, cellular and cordless telephones.

**TO-252(D-Pack)**

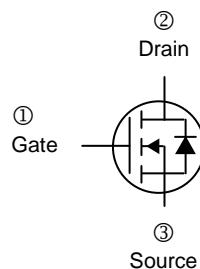


## FEATURES

- Low R<sub>DS(on)</sub> provides higher efficiency and extends battery life.
- Low thermal impedance copper lead frame DPAK saves board space.
- Fast switching speed.
- High performance trench technology.

## PACKAGE INFORMATION

Package	MPQ	Leader Size
TO-252	2.5K	13 inch



REF.	Millimeter		REF.	Millimeter	
	Min.	Max.		Min.	Max.
A	6.35	6.90	J	2.336	REF.
B	4.95	5.50	K	0.89	REF.
C	2.10	2.50	M	0.50	1.14
D	0.43	0.9	N	1.3	1.8
E	6.0	7.5	O	0	0.13
F	2.90	REF.	P	0.58	REF.
G	5.40	6.40			
H	0.60	1.20			

## ABSOLUTE MAXIMUM RATINGS (T<sub>A</sub>=25°C unless otherwise specified)

Parameter	Symbol	Rating	Unit
Drain-Source Voltage	V <sub>DS</sub>	200	V
Gate-Source Voltage	V <sub>GS</sub>	±20	V
Continuous Drain Current  T <sub>C</sub> =25°C	I <sub>D</sub>	9.2	A
Pulsed Drain Current <sup>2</sup>	I <sub>DM</sub>	50	A
Continuous Source Current (Diode Conduction)	I <sub>S</sub>	45	A
Total Power Dissipation  T <sub>C</sub> =25°C	P <sub>D</sub>	50	W
Operating Junction and Storage Temperature Range	T <sub>J</sub> , T <sub>STG</sub>	-55~175	°C

### Thermal Resistance Rating

Maximum Thermal Resistance from Junction to Ambient <sup>1</sup>	R <sub>θJA</sub>	50	°C / W
Maximum Thermal Resistance from Junction to Case	R <sub>θJC</sub>	3	°C / W

Notes:

1. The surface of the device is mounted on a 1" x 1" FR4 Board.
2. The pulse width is limited by the maximum junction temperature

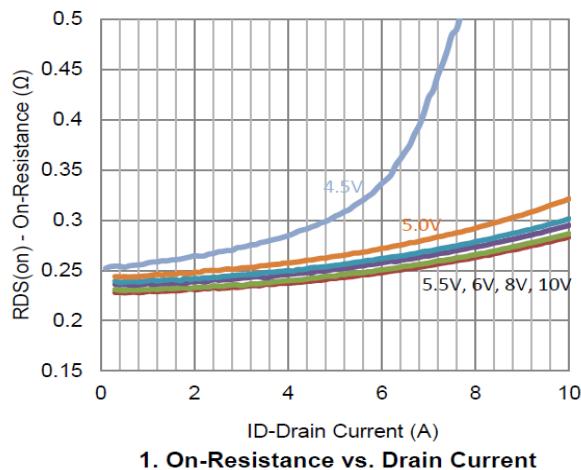
**ELECTRICAL CHARACTERISTICS** ( $T_A=25^\circ\text{C}$  unless otherwise specified)

Parameter	Symbol	Min.	Typ.	Max.	Unit	Test Condition
<b>Static Characteristics</b>						
Gate-Threshold Voltage	$V_{GS(\text{th})}$	1	-	3.5	V	$V_{DS}=V_{GS}$ , $I_D=250\mu\text{A}$
Gate-Body Leakage	$I_{GSS}$	-	-	$\pm 10$	$\mu\text{A}$	$V_{DS}=0\text{V}$ , $V_{GS}=\pm 20\text{V}$
Zero Gate Voltage Drain Current	$I_{DSS}$	-	-	1	$\mu\text{A}$	$V_{DS}=160\text{V}$ , $V_{GS}=0$
		-	-	25		$V_{DS}=160\text{V}$ , $V_{GS}=0$ , $T_J=55^\circ\text{C}$
On-State Drain Current <sup>1</sup>	$I_{D(\text{on})}$	34	-	-	A	$V_{DS}=5\text{V}$ , $V_{GS}=10\text{V}$
Drain-Source On-Resistance <sup>1</sup>	$R_{DS(\text{ON})}$	-	-	400	$\text{m}\Omega$	$V_{GS}=10\text{V}$ , $I_D=4\text{A}$
		-	-	450		$V_{GS}=5.5\text{V}$ , $I_D=3.5\text{A}$
Forward Transconductance <sup>1</sup>	$g_{fs}$	-	10	-	S	$V_{DS}=15\text{V}$ , $I_D=4\text{ A}$
Diode Forward Voltage	$V_{SD}$	-	0.95	-	V	$I_S=23\text{A}$ , $V_{GS}=0$
<b>Dynamic Characteristics</b>						
Input Capacitance	$C_{iss}$	-	807	-	pF	$V_{GS}=0$ $V_{DS}=15\text{V}$ $f = 1\text{MHz}$
Output Capacitance	$C_{oss}$	-	81	-		
Reverse Transfer Capacitance	$C_{rss}$	-	38	-		
Total Gate Charge	$Q_g$	-	9.1	-	nC	$V_{DS}=100\text{V}$ $V_{GS}=5.5\text{V}$ $I_D=4\text{A}$
Gate-Source Charge	$Q_{gs}$	-	3.8	-		
Gate-Drain Charge	$Q_{gd}$	-	3.8	-		
Turn-on Delay Time	$T_{d(on)}$	-	3.7	-	nS	$V_{DD}=100\text{ V}$ $V_{GEN}=10\text{ V}$ $R_L=5\Omega$ $R_{GEN}=6\Omega$ $I_D=4\text{A}$
Rise Time	$T_r$	-	7.7	-		
Turn-off Delay Time	$T_{d(off)}$	-	26.3	-		
Fall Time	$T_f$	-	12.4	-		

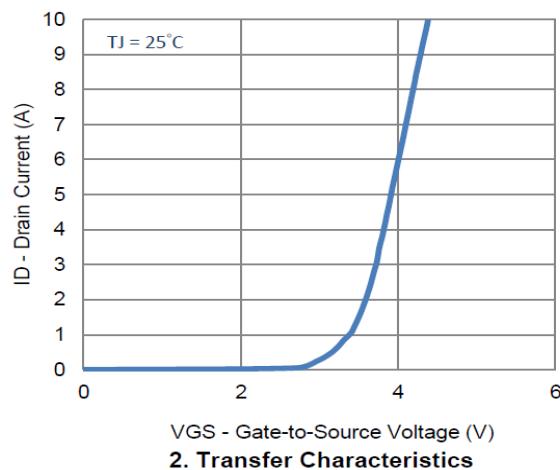
Notes:

1. Pulse test : Pulse width  $\leq 300\mu\text{s}$ , duty cycle  $\leq 2\%$ .

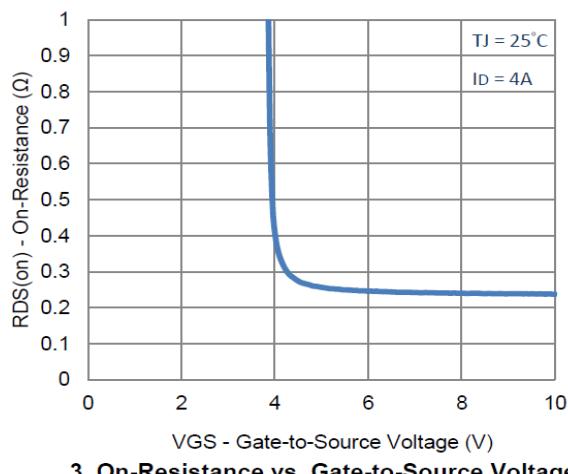
## CHARACTERISTIC CURVE



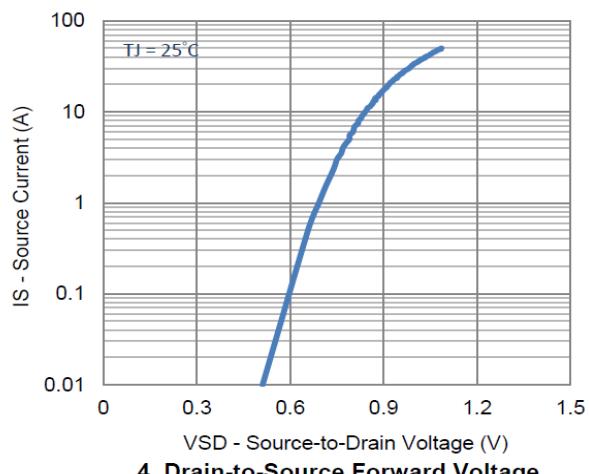
1. On-Resistance vs. Drain Current



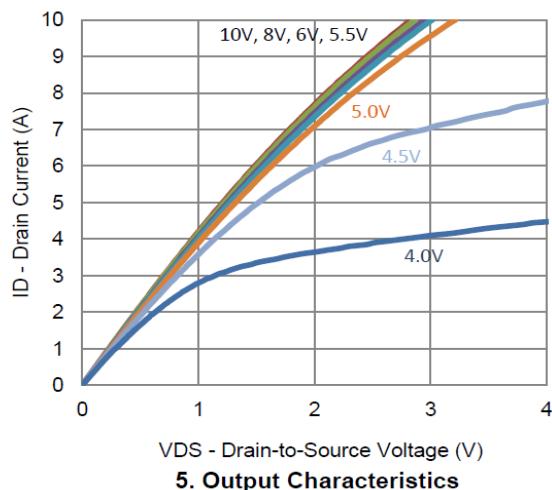
2. Transfer Characteristics



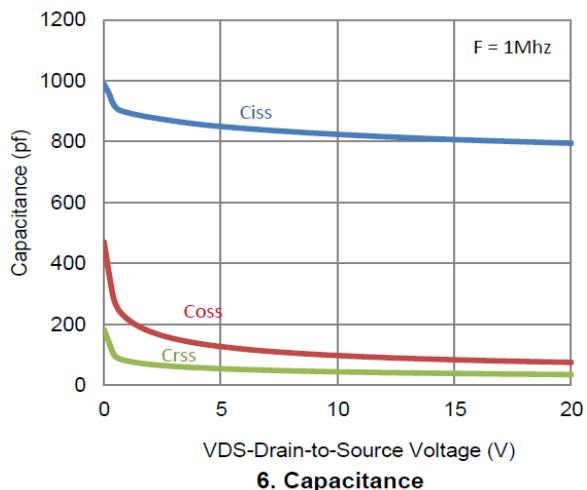
3. On-Resistance vs. Gate-to-Source Voltage



4. Drain-to-Source Forward Voltage



5. Output Characteristics



6. Capacitance

## CHARACTERISTIC CURVE

